EV372453785

Inventor:

H. Daniel Dulman et al.

Title:

Methods Of Forming Aligned Structures With Radiation-

Sensitive Material

Assignee:

Micron Technology, Inc.

Serial No.: Filed Herewith

Filing Date: Filed Herewith

## **INFORMATION DISCLOSURE STATEMENT**

## PURSUANT TO 37 C.F.R. §§1.56, 1.97 AND 1.98

In compliance with 37 C.F.R. §§1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional of co-pending application Serial No. 10/226,005, filed August 21, 2002. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are 37 C.F.R. §1.98(d) and MPEP §609(2). No admission is concerned. made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

David G. Latwesen, Ph.D.

Reg. No. 38,533

WELLS, ST. JOHN P.S.

Form PTO-1449

## U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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LIST OF ART CITED BY APPLICANT

APPLICANT

(Use several sheets if necessary)					H. Daniel Dulman et al.				
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	•			U.S. PATENT DOCUMENTS	•				
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing If Appre	Date opriate
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		ОТІ	HER REFEREN	CES (including Author, Title, Dat	e, Pertinent Pages, Etc.)	)			
	AR	Kobayashi, S. et al., "Development of Simplified Process for KrF Excimer Half-Tone Mask with Chrome-Shielding Method",							
	19th Annual BACUS Sympos. on Photomask Technology, Monterey, CA, 9/99, SPIE Vol. 3873 (1999), pp. 288-29								
	AS	Kobayashi, S. et al., "Development of Simplified Process for KrF Excimer Half-Tone Mask with Chrome-Shielding Method  (II)", 20th Annual BACUS Sympos. on Photomask Technology, Proceedings of SPIE Vol. 4186 (2001), pp.801-809.							
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		if reference considered, whet py of this form with next co		ion is in conformance with MPE applicant.	EP 609; Draw line thro	ugh citation	if not in con	formance and	d not